

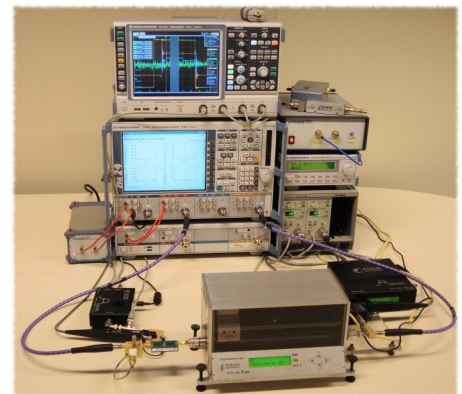
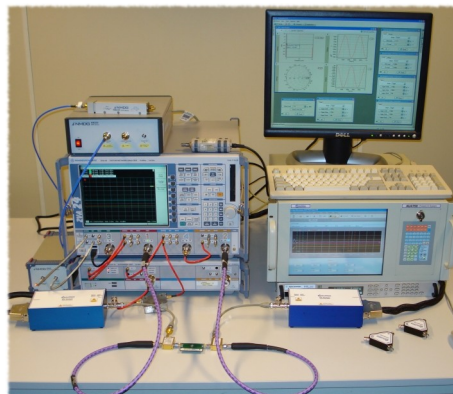
Nonlinear Characterisation under Pulsed DC and RF

KEY Benefits

- Nonlinear characterisation of LDMOS and GaN devices
- Characterisation of thermal and trapping effects
- Reliability testing of semiconductors under HF pulsed conditions
- Improved large-signal models and design kits
- Realistic device characterisation for radar applications
- Fast and complete test capability, even in non-50 Ohm environment
- Customisation by experts to meet the need of the customer

Characterisation in time and frequency domain

Available for Rohde & Schwarz ZVA and ZVT Vector Network Analysers, the NMDG ZVxPlus aims at the accurate characterisation of the nonlinear harmonic behaviour of active RF and HF components. This characterisation can be done under CW, pulsed RF and pulsed DC conditions. The setup can also be extended to perform non-50 Ohm measurements.



The pulsed DC and RF capability is provided by either the Focus MPIV system or the Auriga AU4750 Pulsed IV/RF System and is seamlessly integrated within NMDG ZVxPlus. Other pulsed configurations can be supported by NMDG too. Please contact a NMDG representative for more information.

KEY Capabilities

- True nonlinear harmonic behaviour, including phase information
- Connectorised and on-wafer calibration and measurement
- Accurate time-domain waveforms, e.g. waves, voltages and currents
- Supporting pulsed DC and RF stimulus – response measurement
- Realistic non-50 Ohm conditions, at fundamental and harmonics

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